



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005
& ANSI/NCSL Z540-1-1994

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CALIBRATION

Valid to: June 15, 2013

Certificate Number: AC-1273

I. Electromagnetic - DC/Low Frequency

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
DC Voltage - Source	Up to 220 mV 220 mV to 2.2 V (2.2 to 11) V (11 to 22) V (22 to 220) V 220 V to 1.1 V	8 µV/V + 600 nV 7 µV/V + 1 µV 7 µV/V + 3.5 µV 7 µV/V + 6.5 µV 8 µV/V + 80 µV 9 µV/V + 500 µV	Fluke 5700A Opt 03 Fluke 5725A	OEM and GIDEP Sourced and Laboratory Developed Procedures
DC Voltage - Measure	(10 to 100) mV 100 mV to 1 V (1 to 10) V (10 to 100) V 100 V to 1 kV	5.5 µV/V + 300 nV 5.1 µV/V + 300 nV 4.6 µV/V + 500 nV 6.5 µV/V + 30 µV 16.5 µV/V + 100 µV	HP 3458A Opt 002	
DC Current - Source	Up to 220 µA 220 µA to 2.2 mA (2.2 to 22) mA (22 to 220) mA 220 mA to 2.2 A (2.2 to 3) A (3 to 11) A (11 to 20.5) A	50 µA/A + 8 nA 50 µA/A + 8 nA 50 µA/A + 80 nA 60 µA/A + 800 nA 80 µA/A + 25 µA 380 µA/A + 40 µA 360 µA/A + 480 µA 1 mA/A + 750 µA	Fluke 5700A Opt 03 Fluke 5520A Fluke 5725A Fluke 5520A	
DC Current - Measure	(10 to 100) µA 100 µA to 1 mA (1 to 10) mA (10 to 100) mA 100 mA to 1 A	20 µA/A + 800 pA 20 µA/A + 5 nA 20 µA/A + 50 nA 35 µA/A + 500 nA 110 µA/A + 10 µA	HP 3458A Opt 002	



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Resistance - Source	1 Ω 1.9 Ω 10 Ω 19 Ω 100 Ω 190 Ω 1 kΩ 1.9 kΩ 10 kΩ 19 kΩ 100 kΩ 190 kΩ 1 MΩ 1.9 MΩ 10 MΩ 19 MΩ 100 MΩ	95 μΩ 181 μΩ 280 μΩ 513 μΩ 1.7 mΩ 3.23 mΩ 13 mΩ 24.7 mΩ 120 mΩ 228 mΩ 1.4 Ω 2.66 Ω 20 Ω 40 Ω 400 Ω 893 Ω 11 kΩ	Fluke 5700A Opt 03	
Resistance - Measure	Up to 10 Ω (10 to 100) Ω 100 Ω to 1 kΩ (1 to 10) kΩ (10 to 100) kΩ 100 kΩ to 1 MΩ (1 to 10) MΩ (10 to 100) MΩ 100 MΩ to 1 GΩ	18 μΩ/ Ω + 50 μΩ 13 μΩ/ Ω + 500 μΩ 11 μΩ/ Ω + 500 μΩ 11 μΩ/ Ω + 5 mΩ 11 μΩ/ Ω + 50 mΩ 15 μΩ/ Ω + 2 Ω 53 μΩ/ Ω + 100 Ω 503 μΩ/ Ω + 1 kΩ 5 mΩ/ Ω + 10 kΩ	HP 3458A Opt 002	OEM and GIDEP Sourced and Laboratory Developed Procedures
Capacitance - Source 10 Hz to 10 kHz 10 Hz to 10 kHz 10 Hz to 3 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz 10 Hz to 1 kHz (10 to 600) Hz (10 to 300) Hz (10 to 150) Hz (10 to 120) Hz (10 to 80) Hz Up to 50 Hz Up to 20 Hz Up to 6 Hz Up to 2 Hz Up to 0.6 Hz Up to 0.2 Hz	(190 to 400) pF 400 pF to 1.1 nF (1.1 to 3.3) nF (3.3 to 11) nF (11 to 33) nF (33 to 110) nF (110 to 330) nF 330 nF to 1.1 μF (1.1 to 3.3) μF (3.3 to 11) μF (11 to 33) μF (33 to 110) μF (110 to 330) μF 330 μF to 1.1 mF (1.1 to 3.3) mF (3.3 to 11) mF (11 to 33) mF (33 to 110) mF	5 mF/F + 10 pF 5 mF/F + 10 pF 5 mF/F + 10 pF 2.5 mF/F + 10 pF 2.5 mF/F + 100 pF 2.5 mF/F + 100 pF 2.5 mF/F + 300 pF 2.5 mF/F + 1 nF 2.5 mF/F + 3 nF 2.5 mF/F + 10 nF 4 mF/F + 30 nF 4.5 mF/F + 100 nF 4.5 mF/F + 300 nF 4.5 mF/F + 1 μF 4.5 mF/F + 3 μF 4.5 mF/F + 10 μF 7.5 mF/F + 30 μF 11 mF/F + 100 μF	Fluke 5520A	



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage - Source	<p>Up to 2.2 mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>(2.2 to 22) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>(22 to 220) mV (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>220 mV to 2.2 V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p> <p>(2.2 to 22) V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz</p>	<p>550 µV/V + 4.5 µV 210 µV/V + 4.5 µV 105 µV/V + 4.5 µV 370 µV/V + 4.5 µV 850 µV/V + 7 µV 1.1 mV/V + 13 µV 1.7 mV/V + 25 µV 3.4 mV/V + 25 µV</p> <p>550 µV/V + 5 µV 210 µV/V + 5 µV 105 µV/V + 5 µV 370 µV/V + 5 µV 850 µV/V + 7 µV 1.1 mV/V + 12 µV 1.7 mV/V + 25 µV 3.4 mV/V + 25 µV</p> <p>550 µV/V + 13 µV 210 µV/V + 8 µV 105 µV/V + 8 µV 320 µV/V + 8 µV 850 µV/V + 25 µV 1.1 mV/V + 25 µV 1.7 mV/V + 35 µV 3.4 mV/V + 80 µV</p> <p>500 µV/V + 80 µV 160 µV/V + 25 µV 75 µV/V + 6 µV 120 µV/V + 16 µV 250 µV/V + 70 µV 430 µV/V + 130 µV 1.1 mV/V + 350 µV 2.2 mV/V + 850 µV</p> <p>500 µV/V + 800 µV 160 µV/V + 250 µV 75 µV/V + 60 µV 120 µV/V + 160 µV 250 µV/V + 350 µV 500 µV/V + 1.5 mV 1.3 mV/V + 4.3 mV 2.7 mV/V + 8.5 mV</p>	Fluke 5700A Opt 03	OEM and GIDEP Sourced and Laboratory Developed Procedures



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage - Source (cont.)	(22 to 220) V (10 to 20) Hz (20 to 40) Hz 40 Hz to 20 kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz (300 to 500) kHz 500 kHz to 1 MHz 220 V to 1.1 kV (15 to 50) Hz 50 Hz to 1 kHz	500 $\mu\text{V}/\text{V} + 8 \text{ mV}$ 160 $\mu\text{V}/\text{V} + 2.5 \text{ mV}$ 80 $\mu\text{V}/\text{V} + 800 \mu\text{V}$ 220 $\mu\text{V}/\text{V} + 3.5 \text{ mV}$ 500 $\mu\text{V}/\text{V} + 8 \text{ mV}$ 1.5 $\text{mV}/\text{V} + 90 \text{ mV}$ 4.7 $\text{mV}/\text{V} + 90 \text{ mV}$ 115 $\text{mV}/\text{V} + 190 \text{ mV}$ 400 $\mu\text{V}/\text{V} + 16 \text{ mV}$ 80 $\mu\text{V}/\text{V} + 3.5 \text{ mV}$	Fluke 5700A Opt 03	OEM and GIDEP Sourced and Laboratory Developed Procedures
AC Voltage - Measure	(1 to 10) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1MHz (1 to 4) MHz (4 to 8) MHz (10 to 100) mV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz 100 mV to 1 V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz	300 $\mu\text{V}/\text{V} + 3 \mu\text{V}$ 200 $\mu\text{V}/\text{V} + 1.1 \mu\text{V}$ 300 $\mu\text{V}/\text{V} + 1.1 \mu\text{V}$ 1 $\text{mV}/\text{V} + 1.1 \mu\text{V}$ 5 $\text{mV}/\text{V} + 1.1 \mu\text{V}$ 40 $\text{mV}/\text{V} + 2 \mu\text{V}$ 12 $\text{mV}/\text{V} + 5 \mu\text{V}$ 70 $\text{mV}/\text{V} + 7 \mu\text{V}$ 200 $\text{mV}/\text{V} + 8 \mu\text{V}$ 72 $\mu\text{V}/\text{V} + 4 \mu\text{V}$ 72 $\mu\text{V}/\text{V} + 2 \mu\text{V}$ 142 $\mu\text{V}/\text{V} + 2 \mu\text{V}$ 302 $\mu\text{V}/\text{V} + 2 \mu\text{V}$ 802 $\mu\text{V}/\text{V} + 2 \mu\text{V}$ 3 $\text{mV}/\text{V} + 10 \mu\text{V}$ 10 $\text{mV}/\text{V} + 10 \mu\text{V}$ 15 $\text{mV}/\text{V} + 10 \mu\text{V}$ 40 $\text{mV}/\text{V} + 8 \mu\text{V}$ 150 $\text{mV}/\text{V} + 100 \mu\text{V}$ 72 $\mu\text{V}/\text{V} + 40 \mu\text{V}$ 72 $\mu\text{V}/\text{V} + 20 \mu\text{V}$ 142 $\mu\text{V}/\text{V} + 20 \mu\text{V}$ 302 $\mu\text{V}/\text{V} + 20 \mu\text{V}$ 802 $\mu\text{V}/\text{V} + 20 \mu\text{V}$ 3 $\text{mV}/\text{V} + 100 \mu\text{V}$ 1 $\text{mV}/\text{V} + 100 \mu\text{V}$ 15 $\text{mV}/\text{V} + 100 \mu\text{V}$ 40 $\text{mV}/\text{V} + 800 \mu\text{V}$ 150 $\text{mV}/\text{V} + 1 \text{ mV}$	HP 3458A Opt 002	



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Voltage - Measure (cont.)	(1 to 10) V (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz (1 to 4) MHz (4 to 8) MHz (8 to 10) MHz (10 to 100) V (1 to 40) Hz 40Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 300) kHz 300 kHz to 1 MHz 100 V to 1 kV (1 to 40) Hz 40 Hz to 1 kHz (1 to 20) kHz (20 to 50) kHz (50 to 100) kHz	72 μV/V + 400 μV 72 μV/V + 200 μV 142 μV/V + 200 μV 302 μV/V + 200 μV 802 μV/V + 200 μV 3 mV/V + 1 mV 10 mV/V + 1 mV 15 mV/V + 1 mV 40 mV/V + 8 mV 150 mV/V + 10 mV 200 μV/V + 4 mV 200 μV/V + 2 mV 200 μV/V + 2 mV 350 μV/V + 2 mV 1.2 mV/V + 2 mV 4 mV/V + 10 mV 15 mV/V + 10 mV 400 μV/V + 40 mV 400 μV/V + 20 mV 600 μV/V + 20 mV 1.2 mV/V + 20 mV 3 mV/V + 20 mV	HP 3458A Opt 002	OEM and GIDEP Sourced and Laboratory Developed Procedures
AC Current - Source	(9 to 220) μA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 220 μA to 2.2 mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (2.2 to 22) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz	700 μA/A + 25 nA 350 μA/A + 20 nA 140 μA/A + 16 nA 600 μA/A + 40 nA 1.6 mA/A + 80 nA 700 μA/A + 40 nA 350 μA/A + 35 nA 140 μA/A + 35 nA 600 μA/A + 400 nA 1.6 mA/A + 800 nA 700 μA/A + 400 nA 350 μA/A + 350 nA 140 μA/A + 350 nA 600 μA/A + 4 μA 1.6 mA/A + 8 μA	Fluke 5700A Opt 03	



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current - Source (cont.)	(22 to 220) mA (10 to 20) Hz (20 to 40) Hz 40 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz 220 mA to 2.2 A 20 Hz to 1 kHz (1 to 5) kHz (5 to 10) kHz (2.2 to 11) A 40 Hz to 1kHz (1 to 5) kHz (5 to 10) kHz (11 to 20.5) A (45 to 100) Hz 100Hz to 1 kHz (1 to 5) kHz	700 $\mu\text{A/A} + 4 \mu\text{A}$ 350 $\mu\text{A/A} + 3.5 \mu\text{A}$ 140 $\mu\text{A/A} + 3.5 \mu\text{A}$ 600 $\mu\text{A/A} + 40 \mu\text{A}$ 1.6 mA/A + 80 μA 650 $\mu\text{A/A} + 35 \mu\text{A}$ 750 $\mu\text{A/A} + 80 \mu\text{A}$ 8.5 mA/A + 160 μA 460 $\mu\text{A/A} + 170 \mu\text{A}$ 950 $\mu\text{A/A} + 380 \mu\text{A}$ 3.6 mA/A + 750 μA 1.2 mA/A + 5mA 1.5 mA/A + 5mA 30 mA/A + 5mA	Fluke 5700A Opt 03 Fluke 5725A Fluke 5520A	
AC Current - Measure	(5 to 100) μA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 1 kHz 100 μA to 1 mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz (1 to 10) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (10 to 100) mA (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz (50 to 100) kHz	4 mA/A + 30 nA 1.5 mA/A + 30 nA 600 $\mu\text{A/A} + 30 \text{ nA}$ 600 $\mu\text{A/A} + 30 \text{ nA}$ 4 mA/A + 200 nA 1.5 mA/A + 200 nA 600 $\mu\text{A/A} + 200 \text{ nA}$ 300 $\mu\text{A/A} + 200 \text{ nA}$ 600 $\mu\text{A/A} + 200 \text{ nA}$ 4 mA/A + 400 nA 5.5 mA/A + 1.5 μA 4 mA/A + 2 μA 1.5 mA/A + 2 μA 600 $\mu\text{A/A} + 2 \mu\text{A}$ 300 $\mu\text{A/A} + 2 \mu\text{A}$ 600 $\mu\text{A/A} + 2 \mu\text{A}$ 4 mA/A + 4 μA 4 mA/A + 20 μA 1.5 mA/A + 20 μA 600 $\mu\text{A/A} + 20 \mu\text{A}$ 300 $\mu\text{A/A} + 20 \mu\text{A}$ 600 $\mu\text{A/A} + 20 \mu\text{A}$ 4 mA/A + 40 μA 5.5 mA/A + 150 μA	HP 3458A Opt 002	OEM and GIDEP Sourced and Laboratory Developed Procedures



PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
AC Current - Measure (cont.)	100 mA to 1 A (10 to 20) Hz (20 to 45) Hz (45 to 100) Hz 100 Hz to 5 kHz (5 to 20) kHz (20 to 50) kHz	4 mA/A + 200 µA 1.6 mA/A + 200 µA 800 µA/A + 200 µA 1 mA/A + 200 µA 3 mA/A + 200 µA 10 mA/A + 400 µA	HP 3458A Opt 002	OEM and GIDEP Sourced and Laboratory Developed Procedures
Electrical Simulation of Thermocouple Indicators				
Type B	(600 to 800) °C (800 to 1 000) °C (1 000 to 1 550) °C (1 550 to 1 820) °C	0.51 °C 0.39 °C 0.35 °C 0.38 °C		
Type C	(0 to 150) °C (150 to 650) °C (650 to 1 000) °C (1 000 to 1 800) °C (1 800 to 2 316) °C	0.35 °C 0.3 °C 0.36 °C 0.58 °C 0.97 °C		
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1 000) °C	0.58 °C 0.19 °C 0.16 °C 0.19 °C 0.24 °C		
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1 200) °C	0.32 °C 0.19 °C 0.17 °C 0.2 °C 0.27 °C	Fluke 5520A/SC 1100	
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1 000) °C (1 000 to 1 372) °C	0.38 °C 0.21 °C 0.19 °C 0.3 °C 0.46 °C		
Type L	(-200 to -100) °C (-100 to 800) °C (800 to 900) °C	0.43 °C 0.3 °C 0.2 °C		



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Electrical Simulation of Thermocouple Indicators (cont.)				
Type N	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 410) °C (410 to 1 300) °C	0.46 °C 0.25 °C 0.22 °C 0.21 °C 0.31 °C		
Type R	(0 to 250) °C (250 to 400) °C (400 to 1 000) °C (1 000 to 1 767) °C	0.66 °C 0.4 °C 0.38 °C 0.46 °C		
Type S	(0 to 250) °C (250 to 1 000) °C (1 000 to 1 400) °C (1 400 to 1 767) °C	0.54 °C 0.42 °C 0.43 °C 0.53 °C		
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.73 °C 0.28 °C 0.19 °C 0.17 °C	Fluke 5520A SC 1100	OEM and GIDEP Sourced and Laboratory Developed Procedures
Type U	(-200 to 0) °C (0 to 600) °C	0.65 °C 0.31 °C		
Electrical Simulation of RTDs				
Pt 385 (100 Ω)	(-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.06 °C 0.08 °C 0.1 °C 0.12 °C 0.14 °C 0.27 °C		
Pt 3926 (100 Ω)	(-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.06 °C 0.08 °C 0.1 °C 0.12 °C 0.14 °C		

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(±)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Electrical Simulation of RTDs (cont.)				
Pt 3916 (100 Ω)	(-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.29 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.1 °C 0.12 °C 0.27 °C	Fluke 5520A/SC 1100	OEM and GIDEP Sourced and Laboratory Developed Procedures
Pt 385 (200 Ω)	(-200 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.06 °C 0.14 °C 0.15 °C 0.16 °C 0.18 °C		
Pt 385 (500 Ω)	(-200 to -80) °C (-80 to 100) °C (100 to 260) °C (260 to 400) °C (400 to 600) °C (600 to 630) °C	0.05 °C 0.06 °C 0.07 °C 0.09 °C 0.1 °C 0.13 °C		
Pt 385 (1 000 Ω)	(-200 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 600) °C (600 to 630) °C	0.03 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.27 °C		
PtNi 120 (120 Ω)	(-80 to 100) °C (100 to 260) °C	0.09 °C 0.16 °C		



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Oscilloscopes Amplitude - DC Signal into 50 Ω Load into 1 MΩ Load Amplitude – Square Wave 50 Ω Load 1 MΩ Load Rise Time Leveled Sine Wave Relative to 50 kHz [5 mV to 5.5 V] p-p Time Marker into 50 Ω Load-Source Edge Specs into 50 Ω Load-Source Rise Time 50 Ω load Range (p-p) Wave Generator - Source Amplitude (10 Hz to 10 kHz) Square, Sine, Triangle into 1 MΩ Square, Sine, Triangle into 50 Ω	(-6.6 to 6.6) V (-130 to 130) V ±1 mV to ±6.6 V p-p 10 Hz to 10 kHz ±1 mV to ±130 V p-p 10 Hz to 1 kHz (1 to 10) kHz <300 ps 50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz 5 s to 50 ms 20 ms to 2 ns ≤ 350 ps 5 mV to 2.5 V 1.8 mV to 55 Vp-p 1.8 mV to 2.5 Vp-p	2.5 mV/V + 40 μV 500 μV/V + 40 μV 2.5 mV/V + 40 μV 1 mV/V + 40 μV 2.5 mV/V + 40 μV +0 ps/ -100 ps 35 μV/V + 300 μV 40 μV/V + 300 μV 60 μV/V + 300 μV (25 + 1 000t) parts in 10 ⁶ 2.5 parts in 10 ⁶ (0 /-100) ps 20 mV/V + 200 μV 30 mV/V + 100 μV 30 mV/V + 100 μV	Fluke 5520A/SC 1100	OEM and GIDEP Sourced and Laboratory Developed Procedures



II. Time & Frequency

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Frequency - Source	0.01 Hz to 2 MHz	2.5 μ Hz/Hz + 5 μ Hz	Fluke 5520A	OEM, GIDEP, and Laboratory Developed Procedures
Frequency - Measure	40 Hz to 10 MHz	0.01% of reading	HP 3458A Opt 002	

III. Mechanical

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
Torque	Up to 600 ft-lb	0.29 %	CDI Torque System	OEM and GIDEP Sourced Calibration Procedures
Torque Transducers and Calibrators	(Up to 200) in-lb	0.62 %	Class F Weights with 4 in Radius Wheel	
Scales and Balances	Up to 200 g (200 to 500) g (0.5 to 5) kg (5 to 10) kg (20 to 50) lb (50 to 100) lb (100 to 200) lb (200 to 500) lb	0.33 mg 2.6 mg 33 mg 239 mg 0.02 lb 0.042 lb 0.21 lb 0.46 lb	Class 1 Weights Class F Weights	

IV. Dimensional

PARAMETER / EQUIPMENT	RANGE	CALIBRATION & MEASUREMENT CAPABILITY [EXPRESSED AS UNCERTAINTY(+)]	REFERENCE STANDARD OR EQUIPMENT	METHOD(S)
*Single Axis Dimensional Gaging - Outside	Up to 10 in	(13 + 2.2L) μ in	P&W Universal Supermicrometer	OEM, GIDEP, and Laboratory Developed Procedures
*Thread Plug Gage- Simple Pitch Diameter	Up to 4 in	26.4 μ in	P&W Supermicrometer with Thread Wires	
Micrometers	Up to 4 in (4 to 20) in (20 to 48) in	(54.7 + 7L) μ in (23 + 14.7L) μ in 964 μ in	Grade 2 Gage Blocks with Optical Flats	
Calipers	Up to 4 in (4 to 20) in (20 to 48) in	(54.7 + 7L) μ in (70.9 + 13L) μ in 960 μ in	Grade 2 Gage Blocks	
Height Gages	Up to 4 in (4 to 20) in (20 to 48) in	(54.7 + 7L) μ in (23 + 14.7L) μ in 964 μ in	Grade 2 Gage Blocks with Surface Plate	
Indicators	Up to 4 in	(9.2 + 13.2L) μ in	Grade 2 Gage Blocks	

Notes:

1. Calibration and Measurement Capabilities (CMC) (Expanded Uncertainties) are based on approximately a 95% confidence interval, using a coverage of $k=2$.
2. This laboratory offers calibration services at its laboratory and on-site at customer-designated locations. Since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
3. Capabilities denoted with an asterisk (*) are laboratory-only, not available for on-site calibration activity.
4. CMC for Electromagnetic - DC/Low Frequency do not include possible contributions to uncertainty from the unit under test.
5. The use of (L) signifies an expression of Length in inches.
6. The use of (t) indicates Time in seconds.
7. This scope is part of and must be included with the Certificate of Accreditation No. AC -1273.



Vice President

